JSTAGE	My J-STAGE Sign In
The Journal of Silk Sci	ence and Technology of Japan
The J	apanese Society of Silk Science and Technology
Available Volumes Japanese	>> Publisher Site
Author: ADVANCE	D Volume Page
Keyword: Search	Go
Add to Favorite/Citation Add to Articles Alerts Publications Alerts Publications	

<u>TOP</u> > <u>Available Volumes</u> > <u>Table of Contents</u> > Abstract

ONLINE ISSN : 1881-1698 PRINT ISSN : 1880-8204

The Journal of Silk Science and Technology of Japan

Vol. 14 (2005) 37-44

[Image PDF (1145K)] [References]

Statistical Analysis and Computer Simulation of Random Occurrence of Stripes in the Seriplane Panel of Raw Silk

<u>Majibur Rahman Khan¹⁾, Mikihiko Miura¹⁾, Masaaki Okajima²⁾, Taiki Fujiwara¹⁾, Hideaki Morikawa¹⁾ and Masayuki Iwasa¹⁾</u>

1) Faculty of Textile Science and Technology, Shinshu University

2) The Silk Science Research Institute

(Received August 25, 2005)

Abstract

Seriplane tests have played an important role in classifying the quality of raw silk since the early days of raw silk testing. However, the introduction of machine-based quality inspection has been strongly desired by users of raw silk who are not satisfied with the seriplane tests which depend on judges' personal feelings. In this paper, two probability models were applied to seriplane evenness tests to consider the statistical property of the tests. Under the first model, the probability of test panels judged as Evenness Variation II or III was evaluated. The results revealed the fundamental relationship between the seriplane evenness tests and the size deviation of raw silk. In the second model, the probability of stripes appearing in a seriplane panel was assessed. Computer simulation was carried out to verify the theoretical results.

Keywords

Seriplane test, Evenness test, Raw silk, Statistical model, Computer simulation

[Image PDF (1145K)] [References]

Download Meta of Article[<u>Help</u>] <u>RIS</u> BibTeX To cite this article:

Majibur Rahman Khan, Mikihiko Miura, Masaaki Okajima, Taiki Fujiwara, Hideaki Morikawa and Masayuki Iwasa (2005): Statistical Analysis and Computer Simulation of Random Occurrence of Stripes in the Seriplane Panel of Raw Silk . The Journal of Silk Science and Technology of Japan, 14, 37-44.

JOI JST.JSTAGE/silk/14.37

Copyright (c) 2006 by The Japanese Society of Silk Science and Technology



Japan Science and Technology Information Aggregator, Electronic JSTAGE